

Amendments to the Claims:

This listing of claims replaces all prior versions and listings of claims in the application:

Listing of Claims:

1. (Previously Presented) A data latch circuit which samples a digital signal comprising:
a capacitor means having first and second electrodes;
an inverter whose input terminal is connected to the first electrode; and
a switch connected between the input terminal and an output terminal of the inverter,
wherein the switch is turned ON and a first potential is input to the second electrode of the capacitor means during a reset period, and
wherein the digital signal is input to the second electrode of the capacitor means during a sampling period after the reset period.

2. (Previously Presented) A data latch circuit which samples a digital signal comprising:
a capacitor means having first and second electrodes;
an inverter whose input terminal is connected to the first electrode;
a first switch connected between the input terminal and an output terminal of the inverter;
and
second and third switches connected to the second electrode,
wherein the first switch and the second switch are turned ON to input a first potential to the second electrode of the capacitor means during a reset period, and
wherein the third switch is turned ON to input the digital signal to the second electrode of the capacitor means during a sampling period after the reset period.

3-6. (Canceled)

7. (Previously Presented) A data latch circuit which samples a digital signal comprising:
a first capacitor means having first and second electrodes;

a second capacitor means having third and fourth electrodes;
an inverter whose input terminal is connected to the first electrode and the third electrode;
and
a switch connected between the input terminal and an output terminal of the inverter,
wherein the switch is turned ON and a first potential is input to the second electrode of
the first capacitor means and a second potential is input to the fourth electrode of the second
capacitor means during a reset period, and
wherein the digital signal is input to the second electrode of the first capacitor means and
to the fourth electrode of the second capacitor means during a sampling period after the reset
period.

8. (Previously Presented) A data latch circuit which samples a digital signal comprising:
a first capacitor means having first and second electrodes;
a second capacitor means having third and fourth electrodes;
an inverter whose input terminal is connected to the first electrode and the third electrode;
a first switch connected between the input terminal and an output terminal of the inverter;
second and third switches connected to the second electrode; and
fourth and fifth switches connected to the fourth electrode,
wherein the first switch and the second switch are turned ON to input a first potential to
the second electrode of the first capacitor means while the fourth switch is turned ON to input a
second potential to the fourth electrode of the second capacitor means during a reset period, and
wherein the third switch is turned ON to input the digital signal to the second electrode of
the first capacitor means while the fifth switch is turned ON to input the digital signal to the
fourth electrode of the second capacitor means during a sampling period after the reset period.

9-10. (Canceled)

11. (Previously Presented) The data latch circuit according to, claim 7, wherein the first

potential is a potential of 1 or 0 as the digital signal.

12. (Previously Presented) The data latch circuit according to claim 8, wherein the first potential is a potential of 1 or 0 as the digital signal.

13. (Canceled)

14. (Currently Amended) The data latch circuit according to claim 1, wherein the reset period is determined with a first sampling pulse from a first circuit shift register of a [[the]] preceding stage while the sampling period is determined with a second sampling pulse from a second circuit shift register of a [[the]] present stage.

15. (Currently Amended) The data latch circuit according to claim 2, wherein the reset period is determined with a first sampling pulse from a first circuit shift register of a [[the]] preceding stage while the sampling period is determined with a second sampling pulse from a second circuit shift register of a [[the]] present stage.

16-19. (Canceled)

20. (Currently Amended) The data latch circuit according to claim 7, wherein the reset period is determined with a first sampling pulse from a first circuit shift register of a [[the]] preceding stage while the sampling period is determined with a second sampling pulse from a second circuit shift register of a [[the]] present stage.

21. (Currently Amended) The data latch circuit according to claim 8, wherein the reset period is determined with a first sampling pulse from a first circuit shift register of a [[the]] preceding stage while the sampling period is determined with a second sampling pulse from a second circuit shift register of a [[the]] present stage.

22-23. (Canceled)

24. (Currently Amended) The data latch circuit according to claim 1, wherein the amplitude of the digital signal is comparatively smaller than the potential difference ~~the width of~~ a power supply ~~voltage~~ which is used for the data latch circuit.

25. (Currently Amended) The data latch circuit according to claim 2, wherein the amplitude of the digital signal is comparatively smaller than the potential difference ~~the width of~~ a power supply ~~voltage~~ which is used for the data latch circuit.

26-29. (Canceled)

30. (Currently Amended) The data latch circuit according to claim 7, wherein the amplitude of the digital signal is comparatively smaller than the potential difference ~~the width of~~ a power supply ~~voltage~~ which is used for the data latch circuit.

31. (Currently Amended) The data latch circuit according to claim 8, wherein the amplitude of the digital signal is comparatively smaller than the potential difference ~~the width of~~ a power supply ~~voltage~~ which is used for the data latch circuit.

32-36. (Canceled)

37. (Previously Presented) The data latch circuit according to claim 1, wherein the data latch circuit is formed by using thin film transistors.

38. (Previously Presented) The data latch circuit according to claim 2, wherein the data latch circuit is formed by using thin film transistors.

39-42. (Canceled)

43. (Previously Presented) The data latch circuit according to claim 7, wherein the data latch circuit is formed by using thin film transistors.

44. (Previously Presented) The data latch circuit according to claim 8, wherein the data latch circuit is formed by using thin film transistors.

45-46. (Canceled)

47. (Previously Presented) An electronic device having the data latch circuit according to claim 1, wherein the electronic device is selected from the group consisting of a display, a mobile computer, a game machine, a mobile phone, a navigation system, and a camera.

48. (Previously Presented) An electronic device having the data latch circuit according to claim 2, wherein the electronic device is selected from the group consisting of a display, a mobile computer, a game machine, a mobile phone, a navigation system, and a camera.

49-52. (Canceled)

53. (Previously Presented) An electronic device having the data latch circuit according to claim 7, wherein the electronic device is selected from the group consisting of a display, a mobile computer, a game machine, a mobile phone, a navigation system, and a camera.

54. (Previously Presented) An electronic device having the data latch circuit according to claim 8, wherein the electronic device is selected from the group consisting of a display, a mobile computer, a game machine, a mobile phone, a navigation system, and a camera.

55-56. (Canceled)

57. (New) A semiconductor device comprising:

a data latch circuit which samples a digital signal,

wherein the data latch circuit comprises a capacitor having first and second electrodes, an inverter whose input terminal is connected to the first electrode; and a switch connected between the input terminal and an output terminal of the inverter,

wherein the switch is turned ON and a first potential is input to the second electrode of the capacitor during a reset period, and

wherein the digital signal is input to the second electrode of the capacitor during a sampling period after the reset period.

58. (New) The semiconductor device according to claim 57, wherein the amplitude of the digital signal is comparatively smaller than the potential difference of a power supply which is used for the data latch circuit.

59. (New) The semiconductor device according to claim 57, wherein the data latch circuit is formed by using thin film transistors.

60. (New) An electronic device having the semiconductor device according to claim 57, wherein the electronic device is selected from the group consisting of a display, a mobile computer, a game machine, a mobile phone, a navigation system, and a camera.

61. (New) A semiconductor device comprising:

a data latch circuit which samples a digital signal,

wherein the data latch circuit comprises a capacitor having first and second electrodes, an inverter whose input terminal is connected to the first electrode, a first switch connected

between the input terminal and an output terminal of the inverter; and second and third switches connected to the second electrode,

wherein the first switch and the second switch are turned ON to input a first potential to the second electrode of the capacitor during a reset period, and

wherein the third switch is turned ON to input the digital signal to the second electrode of the capacitor during a sampling period after the reset period.

62. (New) The semiconductor device according to claim 61, wherein the amplitude of the digital signal is comparatively smaller than the potential difference of a power supply which is used for the data latch circuit.

63. (New) The semiconductor device according to claim 61, wherein the data latch circuit is formed by using thin film transistors.

64. (New) An electronic device having the semiconductor device according to claim 61, wherein the electronic device is selected from the group consisting of a display, a mobile computer, a game machine, a mobile phone, a navigation system, and a camera.

65. (New) A semiconductor device comprising:
a data latch circuit which samples a digital signal,
wherein the data latch circuit comprises a first capacitor having first and second electrodes, a second capacitor having third and fourth electrodes, an inverter whose input terminal is connected to the first electrode and the third electrode, and a switch connected between the input terminal and an output terminal of the inverter,
wherein the switch is turned ON and a first potential is input to the second electrode of the first capacitor and a second potential is input to the fourth electrode of the second capacitor during a reset period, and
wherein the digital signal is input to the second electrode of the first capacitor and to the

fourth electrode of the second capacitor during a sampling period after the reset period.

66. (New) The semiconductor device according to claim 65, wherein the first potential is a potential of 1 or 0 as the digital signal.

67. (New) The semiconductor device according to claim 65, wherein the amplitude of the digital signal is comparatively smaller than the potential difference of a power supply which is used for the data latch circuit.

68. (New) The semiconductor device according to claim 65, wherein the data latch circuit is formed by using thin film transistors.

69. (New) An electronic device having the semiconductor device according to claim 65, wherein the electronic device is selected from the group consisting of a display, a mobile computer, a game machine, a mobile phone, a navigation system, and a camera.

70. (New) A semiconductor device comprising:
a data latch circuit which samples a digital signal,
wherein the data latch circuit comprising, a first capacitor having first and second electrodes, a second capacitor having third and fourth electrodes, an inverter whose input terminal is connected to the first electrode and the third electrode, a first switch connected between the input terminal and an output terminal of the inverter, second and third switches connected to the second electrode; and fourth and fifth switches connected to the fourth electrode,

wherein the first switch and the second switch are turned ON to input a first potential to the second electrode of the first capacitor while the fourth switch is turned ON to input a second potential to the fourth electrode of the second capacitor during a reset period, and

wherein the third switch is turned ON to input the digital signal to the second electrode of

the first capacitor while the fifth switch is turned ON to input the digital signal to the fourth electrode of the second capacitor during a sampling period after the reset period.

71. (New) The semiconductor device according to, claim 70, wherein the first potential is a potential of 1 or 0 as the digital signal.

72. (New) The semiconductor device according to claim 70, wherein the amplitude of the digital signal is comparatively smaller than the potential difference of a power supply which is used for the data latch circuit.

73. (New) The semiconductor device according to claim 70, wherein the data latch circuit is formed by using thin film transistors.

74. (New) An electronic device having the semiconductor device according to claim 70, wherein the electronic device is selected from the group consisting of a display, a mobile computer, a game machine, a mobile phone, a navigation system, and a camera.

75. (New) A semiconductor device comprising:
a shift register having at least a first and a second circuit:
at least first and second data latch circuits which sample a digital signal,
wherein each of the first and the second data latch circuits comprises a capacitor having first and second electrodes, an inverter whose input terminal is connected to the first electrode;
and a switch connected between the input terminal and an output terminal of the inverter,
wherein the switch is turned ON and a first potential is input to the second electrode of the capacitor during a reset period, and
wherein the digital signal is input to the second electrode of the capacitor during a sampling period after the reset period.

76. (New) The semiconductor device according to claim 75, wherein the reset period is determined with a first sampling pulse from the first circuit of a preceding stage while the sampling period is determined with a second sampling pulse from the second circuit of a present stage.

77. (New) The semiconductor device according to claim 75, wherein the amplitude of the digital signal is comparatively smaller than the potential difference of a power supply which is used for the first and the second data latch circuits.

78. (New) The semiconductor device according to claim 75, wherein the first and the second data latch circuits are formed by using thin film transistors.

79. (New) An electronic device having the semiconductor device according to claim 75, wherein the electronic device is selected from the group consisting of a display, a mobile computer, a game machine, a mobile phone, a navigation system, and a camera.

80. (New) A semiconductor device comprising:
a shift register having at least a first and a second circuit:
at least first and second data latch circuits which sample a digital signal,
wherein each of the first and the second data latch circuits comprises a capacitor having first and second electrodes, an inverter whose input terminal is connected to the first electrode, a first switch connected between the input terminal and an output terminal of the inverter; and second and third switches connected to the second electrode,
wherein the first switch and the second switch are turned ON to input a first potential to the second electrode of the capacitor during a reset period, and
wherein the third switch is turned ON to input the digital signal to the second electrode of the capacitor during a sampling period after the reset period.

81. (New) The semiconductor device according to claim 80, wherein the reset period is determined with a first sampling pulse from the first circuit of a preceding stage while the sampling period is determined with a second sampling pulse from the second circuit of a present stage.

82. (New) The semiconductor device according to claim 80, wherein the amplitude of the digital signal is comparatively smaller than the potential difference of a power supply which is used for the first and the second data latch circuits.

83. (New) The semiconductor device according to claim 80, wherein the first and the second data latch circuits are formed by using thin film transistors.

84. (New) An electronic device having the semiconductor device according to claim 80, wherein the electronic device is selected from the group consisting of a display, a mobile computer, a game machine, a mobile phone, a navigation system, and a camera.

85. (New) A semiconductor device comprising:
a shift register having at least a first and a second circuit:
at least first and second data latch circuits which sample a digital signal,
wherein each of the first and the second data latch circuits comprises a first capacitor having first and second electrodes, a second capacitor having third and fourth electrodes, an inverter whose input terminal is connected to the first electrode and the third electrode, and a switch connected between the input terminal and an output terminal of the inverter,
wherein the switch is turned ON and a first potential is input to the second electrode of the first capacitor and a second potential is input to the fourth electrode of the second capacitor during a reset period, and
wherein the digital signal is input to the second electrode of the first capacitor and to the fourth electrode of the second capacitor during a sampling period after the reset period.

86. (New) The semiconductor device according to, claim 85, wherein the first potential is a potential of 1 or 0 as the digital signal.

87. (New) The semiconductor device according to claim 85, wherein the reset period is determined with a first sampling pulse from the first circuit of a preceding stage while the sampling period is determined with a second sampling pulse from the second circuit of a present stage.

88. (New) The semiconductor device according to claim 85, wherein the amplitude of the digital signal is comparatively smaller than the potential difference of a power supply which is used for the first and the second data latch circuits.

89. (New) The semiconductor device according to claim 85, wherein the first and the second data latch circuits are formed by using thin film transistors.

90. (New) An electronic device having the semiconductor device according to claim 85, wherein the electronic device is selected from the group consisting of a display, a mobile computer, a game machine, a mobile phone, a navigation system, and a camera.

91. (New) A semiconductor device comprising:
a shift register having at least a first and a second circuit:
at least first and second data latch circuits which sample a digital signal,
wherein each of the first and the second data latch circuits comprises a first capacitor having first and second electrodes, a second capacitor having third and fourth electrodes, an inverter whose input terminal is connected to the first electrode and the third electrode, a first switch connected between the input terminal and an output terminal of the inverter, second and third switches connected to the second electrode; and fourth and fifth switches connected to the

fourth electrode,

wherein the first switch and the second switch are turned ON to input a first potential to the second electrode of the first capacitor while the fourth switch is turned ON to input a second potential to the fourth electrode of the second capacitor during a reset period, and

wherein the third switch is turned ON to input the digital signal to the second electrode of the first capacitor while the fifth switch is turned ON to input the digital signal to the fourth electrode of the second capacitor during a sampling period after the reset period.

92. (New) The semiconductor device according to, claim 91, wherein the first potential is a potential of 1 or 0 as the digital signal.

93. (New) The semiconductor device according to claim 91, wherein the reset period is determined with a first sampling pulse from the first circuit of a preceding stage while the sampling period is determined with a second sampling pulse from the second circuit of a present stage.

94. (New) The semiconductor device according to claim 91, wherein the amplitude of the digital signal is comparatively smaller than the potential difference of a power supply which is used for the first and the second data latch circuits.

95. (New) The semiconductor device according to claim 91, wherein the first and the second data latch circuits are formed by using thin film transistors.

96. (New) An electronic device having the semiconductor device according to claim 91, wherein the electronic device is selected from the group consisting of a display, a mobile computer, a game machine, a mobile phone, a navigation system, and a camera.